

INFORMATION DISCLOSURE CITATION

PTO-1449

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007325-077APPLICATION NO.
UnassignedAPPLICANT
Frank J. KOCH et al.FILING DATE
September 15, 1995GROUP
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U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
XXH	4,695,797	09-1987	DEUTSCH ET AL.	324	230	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

XXH	Verax Systems, Inc.; SPC FocusPLUS; 1993; 9 pages;
XXH	Introductory Pages of User's Manual for SPC FocusPLUS; Verax Systems, Inc.; 1994; 15 pages.
XXH	SPC FocusPLUS User's Manual; Chapter 6; Variables Data Collection; 28 pages.
XXH	Interface between Elcometer...; Instruction Sheet; pages 4316-1 through 4316-3.
XXH	Elcometer 500 Literature; elcometer 500; 8 pages; 1986.
XXH	Elcometer 500; Instruction Manual; Publication ELC0500/0886/3.05; 55 pages;
XXH	Leptoskop Layer Thickness Gauges; 4 pages
XXH	NDTnet; Karl Deutsch Handterminal 2051 Layer Thickness Measuring with or without PC; October 1998; 1 page.
XXH	Sonden für LEPTOSKOP 2040 in Originalgröße; 1995; 1 page.

EXAMINER

Initial & Serial No.
~~XXH~~ ~~VO~~

DATE CONSIDERED

12/8/09

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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.